

CSD17556Q5B 30V N 通道 NexFET™ 功率金属氧化物半导体场效应晶体管 (MOSFET)

1 特性

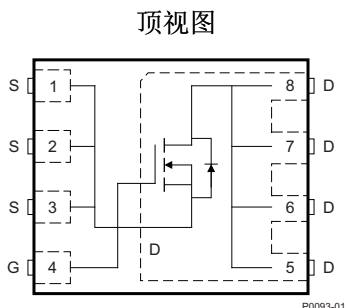
- 极低电阻
- 超低 Q_g 和 Q_{gd}
- 低热阻
- 雪崩级
- 无铅引脚镀层
- 符合 RoHS 标准
- 无卤素
- SON 5mm x 6mm 塑料封装

2 应用范围

- 网络互联、电信和计算系统中的负载点同步降压
- 同步整流
- 有源操作和热插拔 应用

3 说明

此 30V、1.2m Ω 、5mm x 6mm NexFET™ 功率 MOSFET 旨在最大限度地减小同步整流和其他功率转换应用中的 损耗。



产品概要

$T_A = 25^\circ\text{C}$		典型值		单位
V_{DS}	漏源电压	30		V
Q_g	总栅极电荷 (4.5V)	30		nC
Q_{gd}	栅极电荷 (栅极到漏极)	7.5		nC
$R_{DS(on)}$	漏源导通电阻	$V_{GS} = 4.5\text{V}$	1.5	m Ω
		$V_{GS} = 10\text{V}$	1.2	
$V_{GS(th)}$	阈值电压	1.4		V

器件信息(1)

器件	数量	包装介质	封装	发货
CSD17556Q5B	2500	13 英寸卷带	SON 5.00-mm x 6.00-mm 塑料封装	卷带封装
CSD17556Q5BT	250			

(1) 如需了解所有可用封装, 请参阅数据表末尾的可订购产品附录。

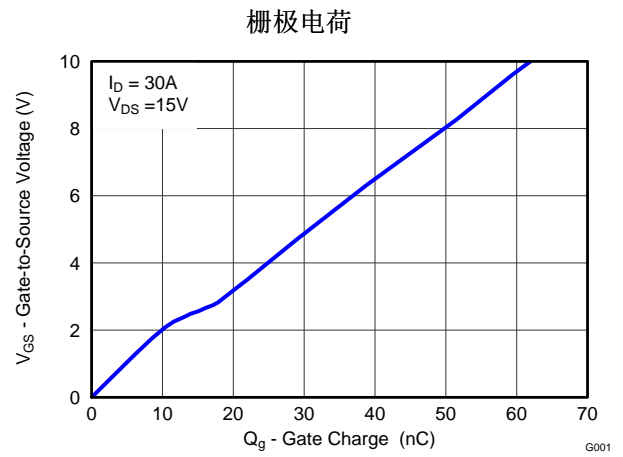
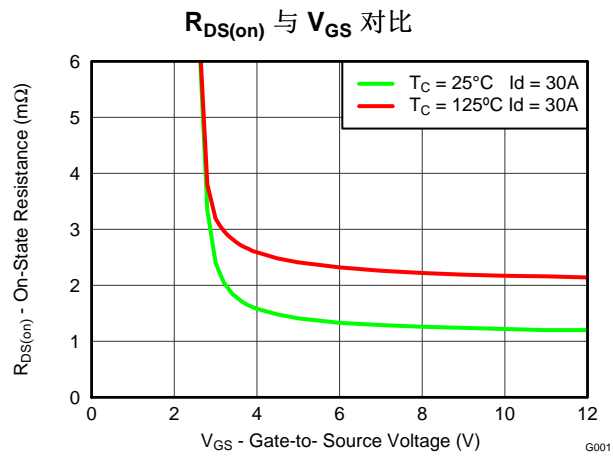
绝对最大额定值

$T_A = 25^\circ\text{C}$		值	单位
V_{DS}	漏源电压	30	V
V_{GS}	栅源电压	± 20	V
I_D	持续漏极电流 (受封装限制)	100	A
	持续漏极电流 (受芯片限制), $T_C = 25^\circ\text{C}$ 时测得	215	
	持续漏极电流 ⁽¹⁾	34	
I_{DM}	脉冲漏极电流, $T_A = 25^\circ\text{C}$ 时测得 ⁽¹⁾⁽²⁾	400	A
P_D	功率耗散 ⁽¹⁾	3.1	W
	功率耗散, $T_C = 25^\circ\text{C}$ 时测得	191	
T_J 、 T_{stg}	工作结温、 储存温度	-55 至 150	$^\circ\text{C}$
E_{AS}	雪崩能量, 单一脉冲 $I_D = 100\text{A}$, $L = 0.1\text{mH}$, $R_G = 25\Omega$	500	mJ

(1) 典型 $R_{\theta JA} = 40^\circ\text{C}/\text{W}$ (当在 0.06 英寸 [1.52mm] 厚的 FR4 PCB 上将其安装在 1 平方英寸 [6.45cm²] 2 oz [0.071mm] 厚的铜焊盘上时)。

(2) 最大 $R_{\theta JC} = 1.3^\circ\text{C}/\text{W}$, 脉冲持续时间 $\leq 100\mu\text{s}$, 占空比 $\leq 1\%$ 。





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4 修订历史记录

Changes from Revision C (January 2017) to Revision D Page

- 更正了首页格式错误 **2**

Changes from Revision B (August 2014) to Revision C Page

- 已更改 器件信息表中的部件编号 **1**
- 已添加 接收文档更新通知部分和社区资源部分至器件和文档支持部分 **8**

Changes from Revision A (October 2013) to Revision B Page

- 将最大脉冲漏极电流增至 400A。 **1**
- 更新了脉冲漏极电流条件 **1**
- Updated [Figure 1](#) to a normalized $R_{\theta JC}$ curve **5**
- Updated the SOA in [Figure 10](#) **7**
- 更新了机械制图和尺寸表以显示之前未知的尺寸 **9**

Changes from Original (March 2013) to Revision A Page

- 更新了机械数据部分中的尺寸表，新增 DIM“H”值 **9**

5 Specifications

5.1 Electrical Characteristics

 $T_A = 25^\circ\text{C}$ (unless otherwise stated)

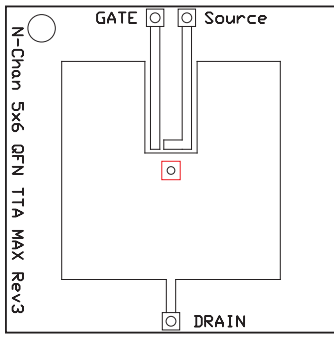
PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
STATIC CHARACTERISTICS						
V_{DSS}	Drain-to-source voltage	$V_{GS} = 0\text{ V}, I_{DS} = 250\ \mu\text{A}$	30			V
I_{DSS}	Drain-to-source leakage current	$V_{GS} = 0\text{ V}, V_{DS} = 24\text{ V}$			1	μA
I_{GSS}	Gate-to-source leakage current	$V_{DS} = 0\text{ V}, V_{GS} = 20\text{ V}$			100	nA
$V_{GS(th)}$	Gate-to-source threshold voltage	$V_{DS} = V_{GS}, I_{DS} = 250\ \mu\text{A}$	1.15	1.4	1.65	V
$R_{DS(on)}$	Drain-to-source on-resistance	$V_{GS} = 4.5\text{ V}, I_{DS} = 40\text{ A}$		1.5	1.8	m Ω
		$V_{GS} = 10\text{ V}, I_{DS} = 40\text{ A}$		1.2	1.4	
g_{fs}	Transconductance	$V_{DS} = 15\text{ V}, I_{DS} = 40\text{ A}$		197		S
DYNAMIC CHARACTERISTICS						
C_{iss}	Input capacitance	$V_{GS} = 0\text{ V}, V_{DS} = 15\text{ V},$ $f = 1\text{ MHz}$		5400	7020	pF
C_{oss}	Output capacitance			1770	2310	pF
C_{rss}	Reverse transfer capacitance			68	88	pF
R_G	Series gate resistance			0.7	1.4	Ω
Q_g	Gate charge total (4.5 V)	$V_{DS} = 15\text{ V}, I_{DS} = 40\text{ A}$		30	39	nC
Q_{gd}	Gate charge gate-to-drain			7.5		nC
Q_{gs}	Gate charge gate-to-source			11		nC
$Q_{g(th)}$	Gate charge at V_{th}			6.1		nC
Q_{oss}	Output charge	$V_{DS} = 15\text{ V}, V_{GS} = 0\text{ V}$		48		nC
$t_{d(on)}$	Turnon delay time	$V_{DS} = 15\text{ V}, V_{GS} = 4.5\text{ V},$ $I_{DS} = 40\text{ A}, R_G = 2\ \Omega$		14		ns
t_r	Rise time			26		ns
$t_{d(off)}$	Turnoff delay time			27		ns
t_f	Fall time			12		ns
DIODE CHARACTERISTICS						
V_{SD}	Diode forward voltage	$I_{SD} = 40\text{ A}, V_{GS} = 0\text{ V}$		0.8	1	V
Q_{rr}	Reverse recovery charge	$V_{DD} = 15\text{ V}, I_F = 40\text{ A}, di/dt = 300\text{ A}/\mu\text{s}$		68		nC
t_{rr}	Reverse recovery time			36		ns

5.2 Thermal Information

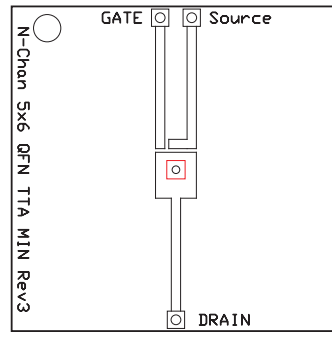
 $T_A = 25^\circ\text{C}$ (unless otherwise stated)

THERMAL METRIC		MIN	TYP	MAX	UNIT
$R_{\theta JC}$	Junction-to-case thermal resistance ⁽¹⁾			1.3	$^\circ\text{C}/\text{W}$
$R_{\theta JA}$	Junction-to-ambient thermal resistance ⁽¹⁾⁽²⁾			50	

- $R_{\theta JC}$ is determined with the device mounted on a 1-in² (6.45-cm²), 2-oz (0.071-mm) thick Cu pad on a 1.5-in × 1.5-in (3.81-cm × 3.81-cm), 0.06-in (1.52-mm) thick FR4 PCB. $R_{\theta JC}$ is specified by design, whereas $R_{\theta JA}$ is determined by the user's board design.
- Device mounted on FR4 material with 1-in² (6.45-cm²), 2-oz (0.071-mm) thick Cu.



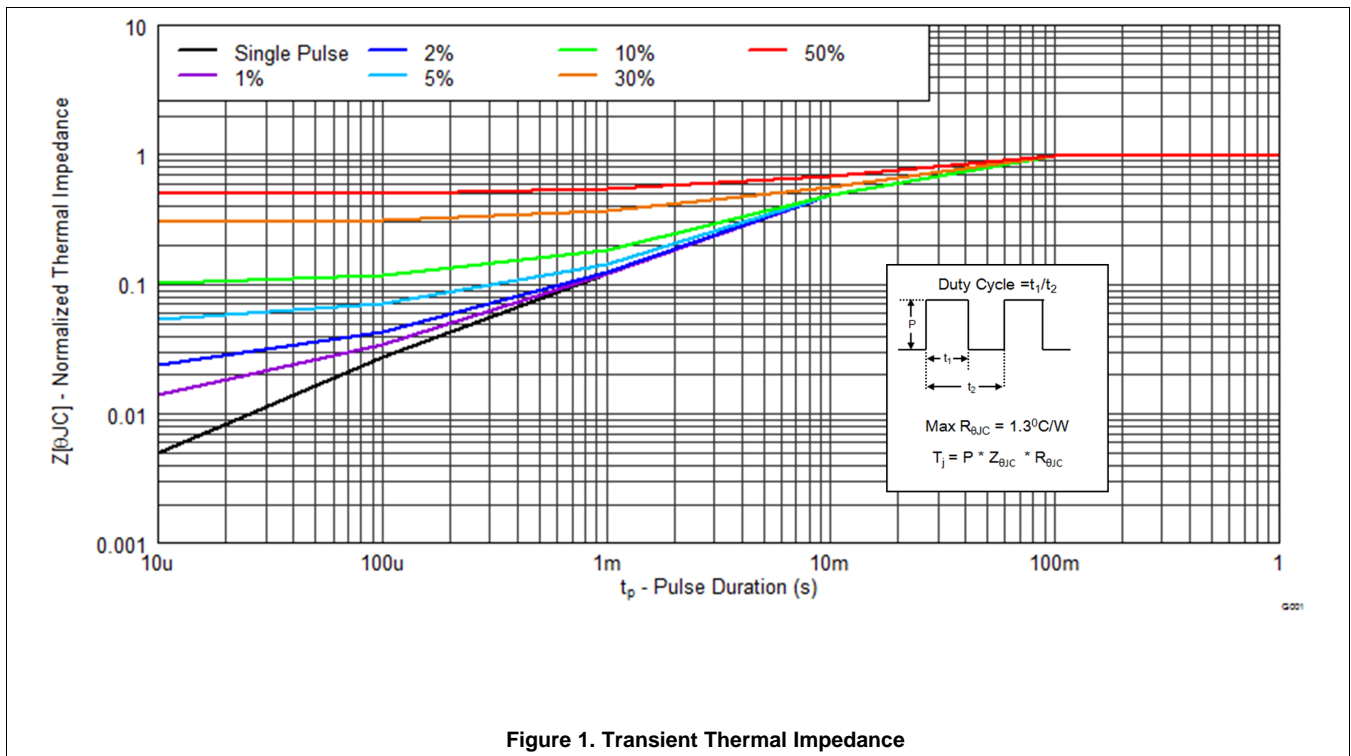
Max $R_{\theta JA} = 50^{\circ}\text{C/W}$
when mounted on 1-in²
(6.45-cm²) of
2-oz (0.071-mm) thick
Cu.



Max $R_{\theta JA} = 125^{\circ}\text{C/W}$
when mounted on a
minimum pad area of
2-oz (0.071-mm) thick
Cu.

5.3 Typical MOSFET Characteristics

$T_A = 25^{\circ}\text{C}$ (unless otherwise stated)



Typical MOSFET Characteristics (continued)

T_A = 25°C (unless otherwise stated)

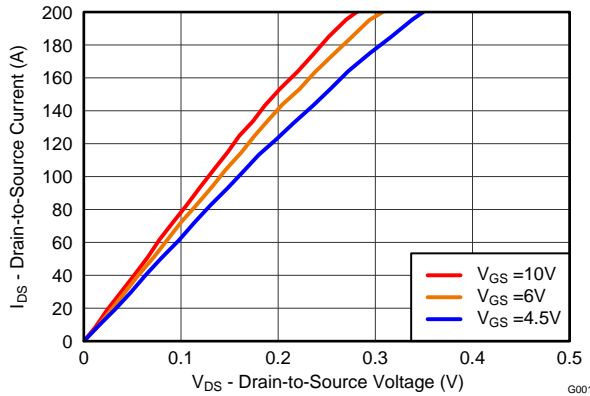


Figure 2. Saturation Characteristics

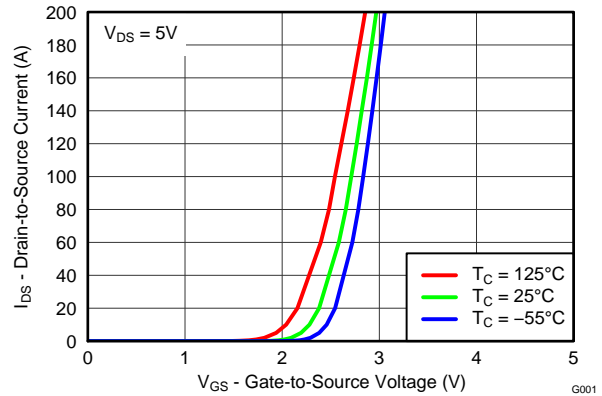


Figure 3. Transfer Characteristics

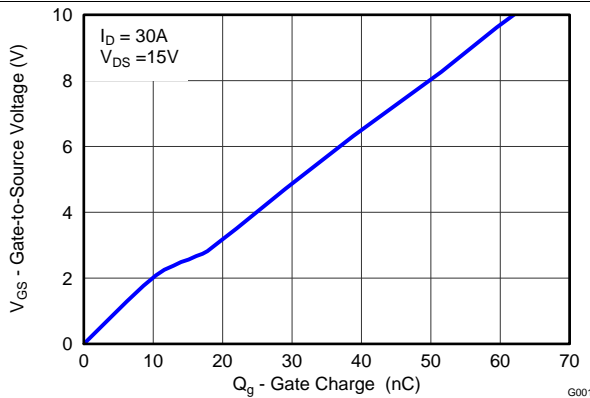


Figure 4. Gate Charge

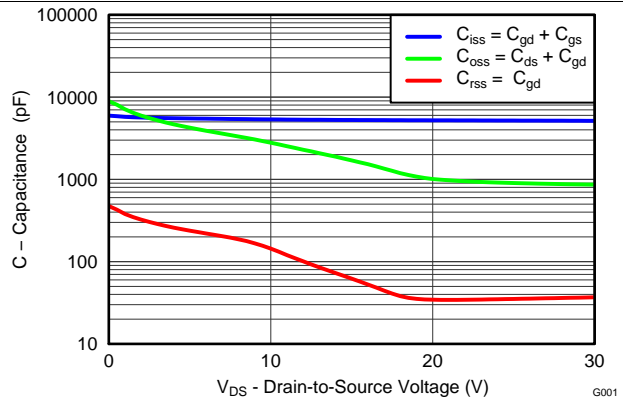


Figure 5. Capacitance

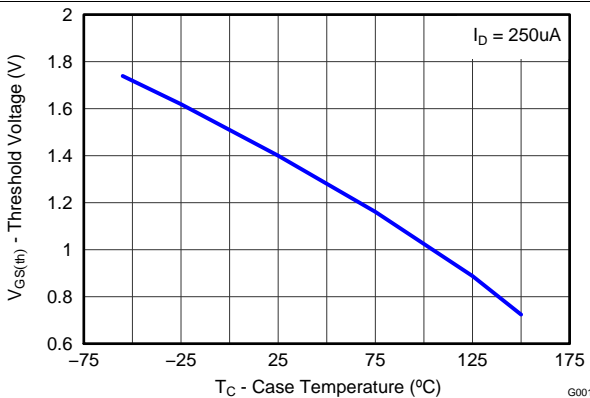


Figure 6. Threshold Voltage vs Temperature

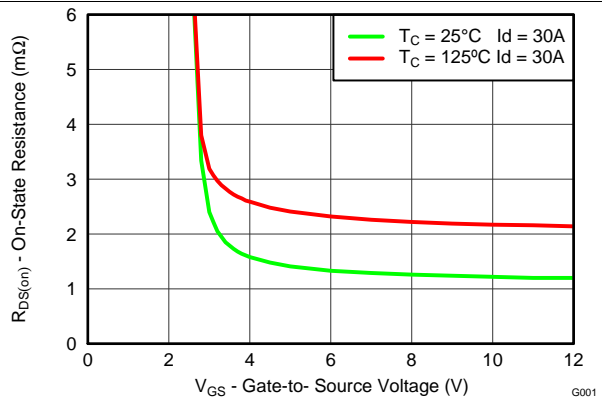


Figure 7. On-State Resistance vs Gate-to-Source Voltage

Typical MOSFET Characteristics (continued)

T_A = 25°C (unless otherwise stated)

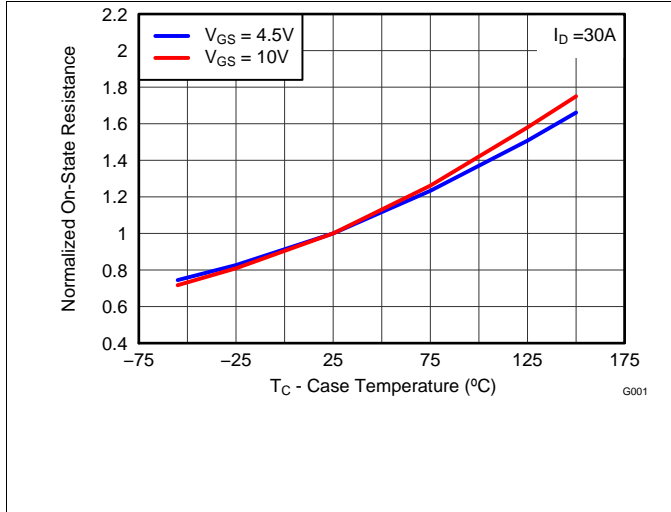


Figure 8. Normalized On-State Resistance vs Temperature

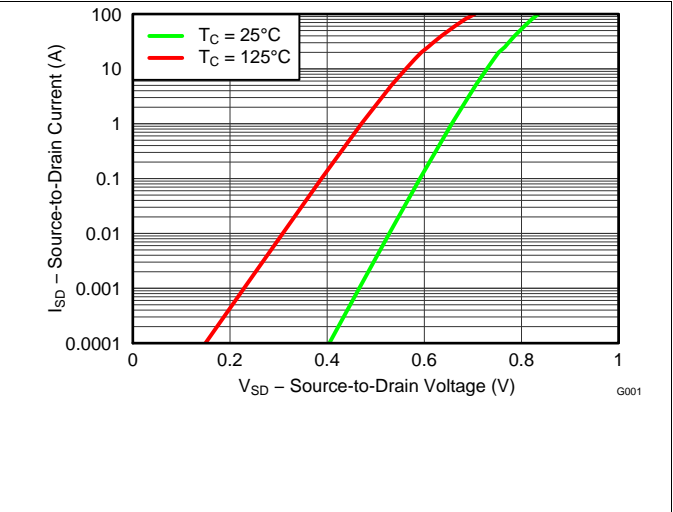


Figure 9. Typical Diode Forward Voltage

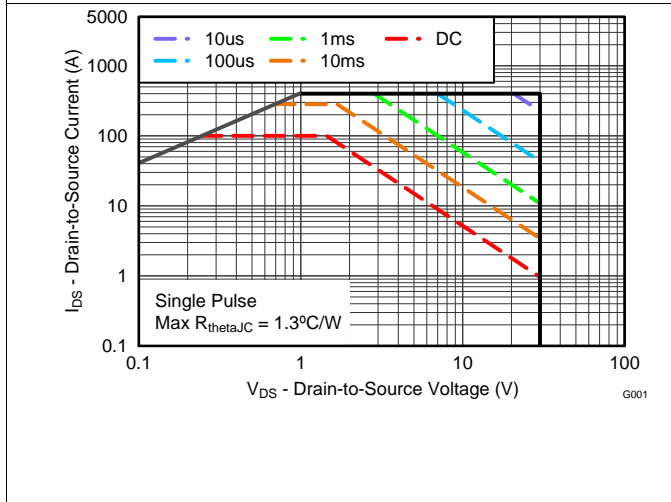


Figure 10. Maximum Safe Operating Area (SOA)

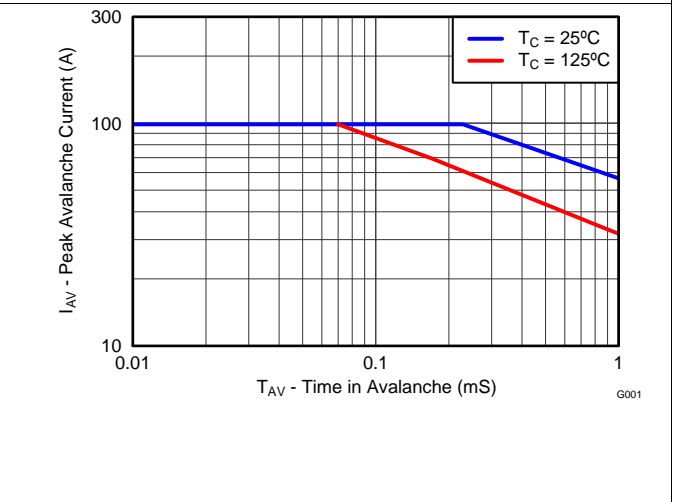


Figure 11. Single Pulse Unclamped Inductive Switching

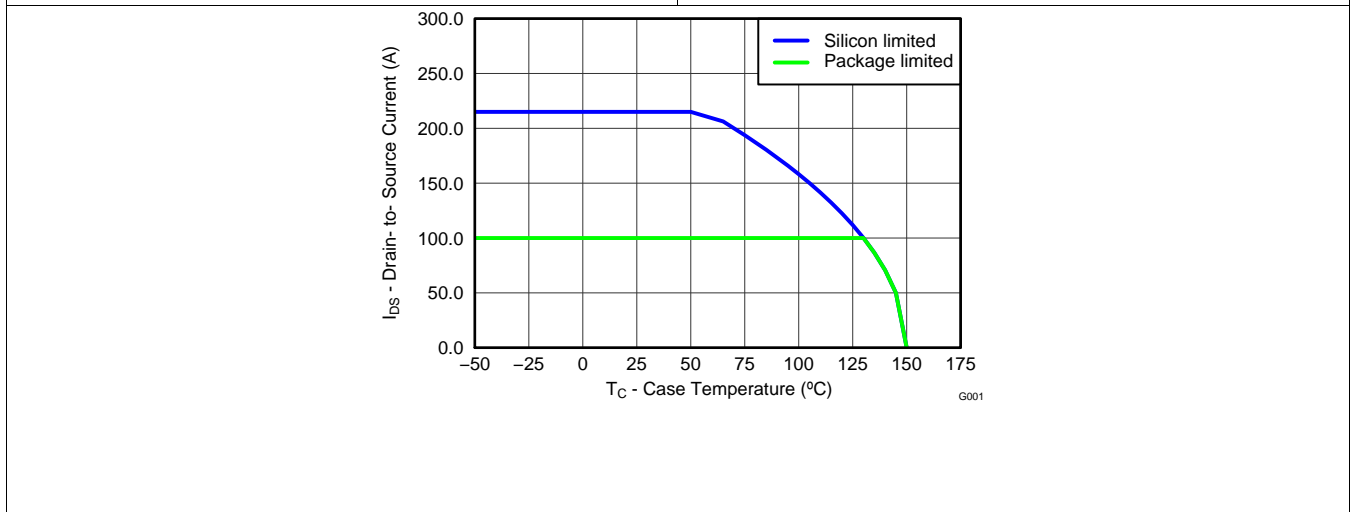


Figure 12. Maximum Drain Current vs Temperature

6 器件和文档支持

6.1 接收文档更新通知

如需接收文档更新通知，请导航至 TI.com 上的器件产品文件夹。单击右上角的 [通知我](#) 进行注册，即可每周接收产品信息更改摘要。有关更改的详细信息，请查看任何已修订文档中包含的修订历史记录。

6.2 社区资源

下列链接提供到 TI 社区资源的连接。链接的内容由各个分销商“按照原样”提供。这些内容并不构成 TI 技术规范，并且不一定反映 TI 的观点；请参阅 TI 的 [《使用条款》](#)。

TI E2E™ 在线社区 [TI 的工程师对工程师 \(E2E\) 社区](#)。此社区的创建目的在于促进工程师之间的协作。在 e2e.ti.com 中，您可以咨询问题、分享知识、拓展思路并与同行工程师一道帮助解决问题。

设计支持 [TI 参考设计支持](#) 可帮助您快速查找有帮助的 E2E 论坛、设计支持工具以及技术支持的联系信息。

6.3 商标

NexFET, E2E are trademarks of Texas Instruments.
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6.4 静电放电警告



这些装置包含有限的内置 ESD 保护。存储或装卸时，应将导线一起截短或将装置放置于导电泡棉中，以防止 MOS 门极遭受静电损伤。

6.5 Glossary

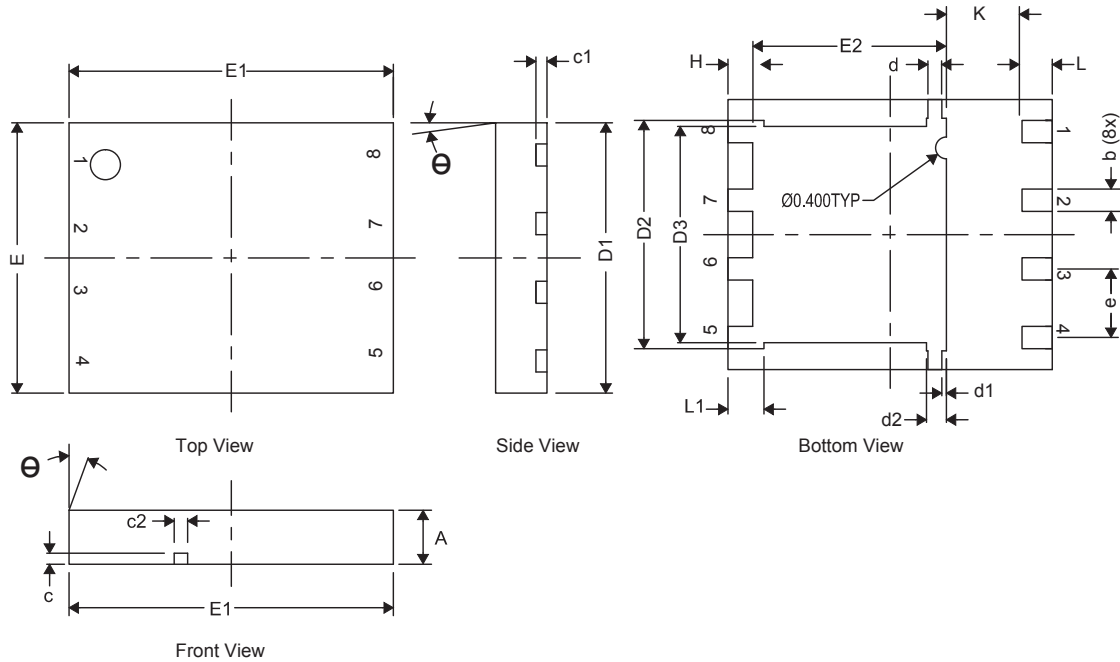
[SLYZ022](#) — *TI Glossary*.

This glossary lists and explains terms, acronyms, and definitions.

7 机械、封装和可订购信息

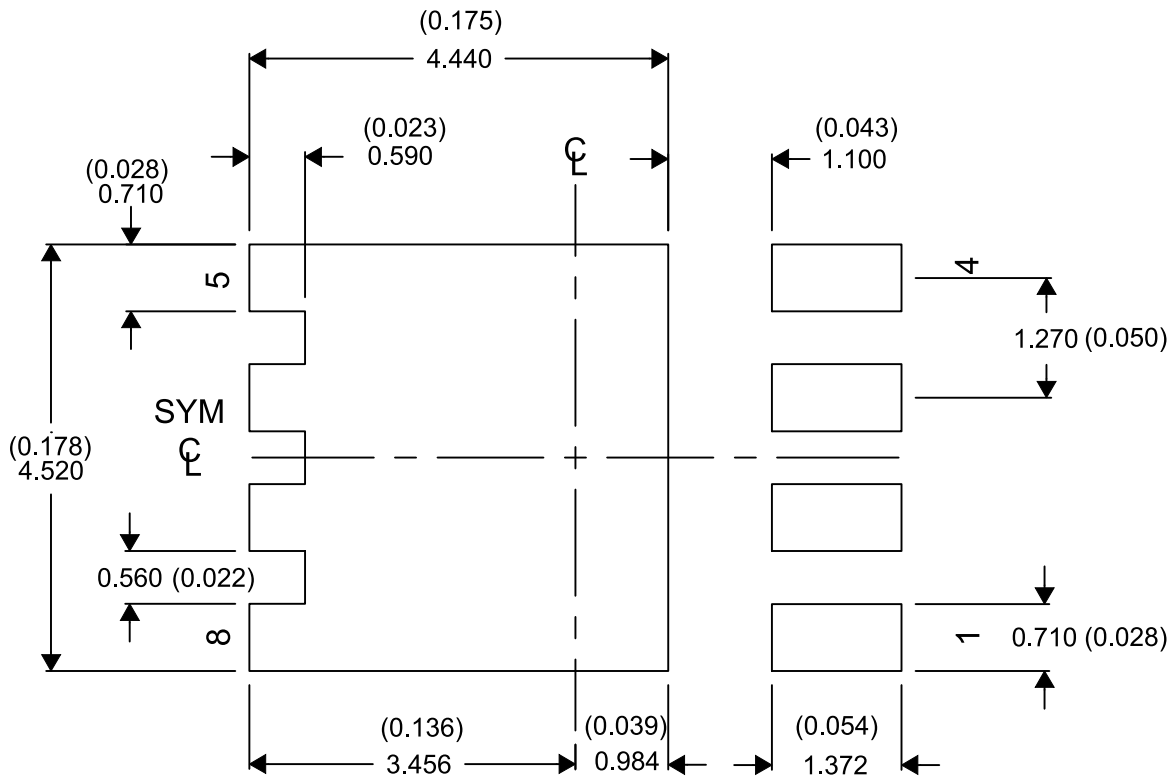
以下页面包含机械、封装和可订购信息。这些信息是指定器件的最新可用数据。数据如有变更，恕不另行通知和修订此文档。要获得这份数据表的浏览器版本，请查阅左侧的导航栏。

7.1 Q5B 封装尺寸



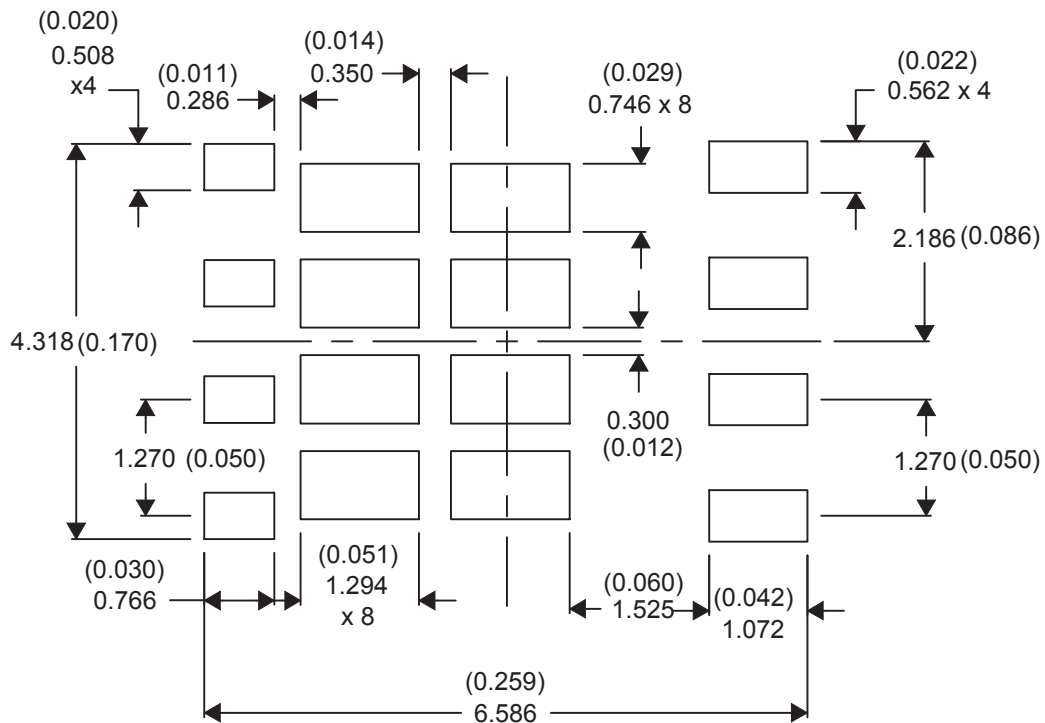
DIM	毫米		
	最小值	标称值	最大值
A	0.80	1.00	1.05
b	0.36	0.41	0.46
c	0.15	0.20	0.25
c1	0.15	0.20	0.25
c2	0.20	0.25	0.30
D1	4.90	5.00	5.10
D2	4.12	4.22	4.32
D3	3.90	4.00	4.10
d	0.20	0.25	0.30
d1	0.085 典型值		
d2	0.319	0.369	0.419
E	4.90	5.00	5.10
E1	5.90	6.00	6.10
E2	3.48	3.58	3.68
e	1.27 典型值		
H	0.36	0.46	0.56
L	0.46	0.56	0.66
L1	0.57	0.67	0.77
θ	0°	—	—
K	1.40 典型值		

7.2 建议 PCB 布局

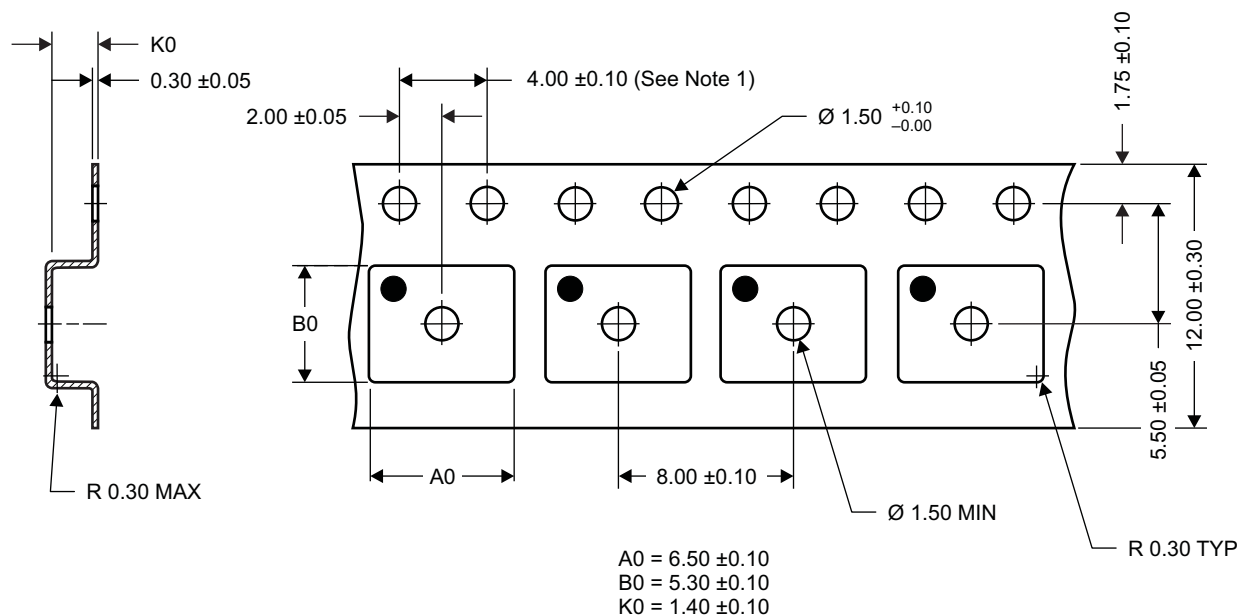


如需了解针对 PCB 设计的建议电路布局，请参阅《通过 PCB 布局技巧来减少振铃》(SLPA005)。

7.3 建议模板布局



7.4 Q5B 卷带信息





M0138-01

注释:

1. 10 个链齿孔的累积容差为 ± 0.2 。
2. 每 100mm 长度的翘曲不能超过 1mm，在 250mm 长度上不累积。
3. 材料：黑色防静电聚苯乙烯。
4. 全部尺寸为 mm（除非另外注明）。
5. 高于孔眼底部 0.3mm 的平面上测量得到 A0 和 B0 值。

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
CSD17556Q5B	ACTIVE	VSON-CLIP	DNK	8	2500	RoHS-Exempt & Green	SN	Level-1-260C-UNLIM	-55 to 150	CSD17556	
CSD17556Q5BT	ACTIVE	VSON-CLIP	DNK	8	250	RoHS-Exempt & Green	SN	Level-1-260C-UNLIM	-55 to 150	CSD17556	

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) **RoHS:** TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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